

Andrew G. Repjar (M'77-SM'82) received the B.E.E., M.S. and Ph.D. degrees from The Ohio State University, Columbus, OH, in 1964, 1966, and 1970, respectively. His fields of interest include electromagnetic theory, antenna theory, properties of materials, radar cross section metrology, and satellite communication measurements. He is Leader of the Antenna and Materials Metrology Group in the Electromagnetic Fields Division of the National Institute of Standards and Technology, Boulder, CO, where since 1975 he has utilized both near-field and far-field measurement techniques to determine antenna parameters used in radar, satellite and communications systems. Since 1992, he is also responsible for leading a metrology program on the characterization of the microwave properties of materials. These materials include thin films, substrates, and other materials used in antenna lenses, radomes, microwave absorbers, and microstrip antennas.

In 1989 and 1987 respectively, he received the Department of Commerce Silver Medal and Bronze Medal Awards, for his outstanding contributions in extending the practical utility of NIST-developed methods for measurements on antennas. Prior to 1975, he worked at Rockwell International, Columbus, OH, and at the ElectroScience Laboratory at The Ohio State University. Dr. Repjar has published many reports and papers in the antenna metrology areas and has given lectures in short courses on antenna measurements at NIST and industrial facilities. He served on the Administrative Committee in the Antennas and Propagation Society from 1993-1995. He also serves on the Antenna Standards Committee, and chairs the Committee on Support for AP-S History. He served in 1991 as President of the Antenna Measurement Techniques Association, and in 1989-90 as Vice President of that organization.